

# Nion UltraSTEM™ 100

## Dedicated Scanning Transmission Electron Microscope

### Instrument Specifications:

- Cold field emission gun
- 3<sup>rd</sup> generation C<sub>3</sub>/C<sub>5</sub> aberration corrector
- 60-100kV operation
- <1Å spatial resolution at 100 kV
- <1.1Å spatial resolution at 60 kV
- >0.5nA of current with atom-sized probe
- <350meV energy resolution at 100 kV
- Gatan Enfina EELS
- Ultra-stable sample stage
- Up to 5 samples can be loaded/exchanged with no vacuum degradation
- Flexible electron optics (diffraction and CTEM modes)

### Instrument Applications:

Atomic resolution imaging and spectroscopy at mid- and low-voltage with single atom sensitivity

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